PSMN050-80PS

N-channel 80 V 50 mΩ standard level MOSFET

Rev. 01 — 10 June 2009 Product data sheet

1. Product profile

1.1 General description

Standard level N-channel MOSFET in TO220 package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Repetitive avalanche rated
- Suitable for standard level gate drive sources

1.3 Applications

- DC-to-DC converters
- Load switching
- Motor control
- Server power supplies

1.4 Quick reference data

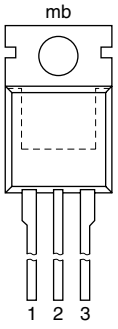
Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see Figure 1	-	-	22	A
Dynamic characteristics						
Q_{GD}	gate-drain charge	V_{GS} = 10 V; I_D = 25 A; V_{DS} = 40 V; see Figure 14; see Figure 15	-	2.3	-	nC

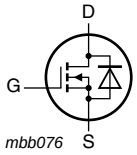
2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain		
3	S	source		



SOT78
(TO-220AB; SC-46)



3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN050-80PS	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

4. Limiting values

Table 4. Limiting values

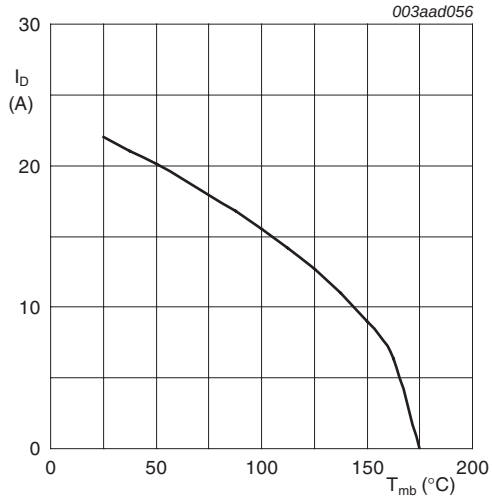
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25$ °C; $T_j \leq 175$ °C		-	80	V
V_{DGR}	drain-gate voltage	$T_j \geq 25$ °C; $T_j \leq 175$ °C; R_{GS} = 20 kΩ		-	80	V
V_{GS}	gate-source voltage			-20	20	V
I_D	drain current	V_{GS} = 10 V; T_{mb} = 100 °C; see Figure 1		-	16	A
		V_{GS} = 10 V; T_{mb} = 25 °C; see Figure 1		-	22	A
I_{DM}	peak drain current	$t_p \leq 10$ µs; pulsed; T_{mb} = 25 °C		-	88	A
P_{tot}	total power dissipation	T_{mb} = 25 °C; see Figure 2		-	56	W
T_{stg}	storage temperature			-55	175	°C
T_j	junction temperature			-55	175	°C
Source-drain diode						
I_S	source current	T_{mb} = 25 °C		-	22	A
I_{SM}	peak source current	$t_p \leq 10$ µs; pulsed; T_{mb} = 25 °C		-	88	A
Avalanche ruggedness						
$E_{DS(AL)R}$	repetitive drain-source avalanche energy	see Figure 3	[1][2] [3]	-	-	J
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 22 A; $V_{sup} \leq 80$ V; R_{GS} = 50 Ω; unclamped		-	18	mJ

[1] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

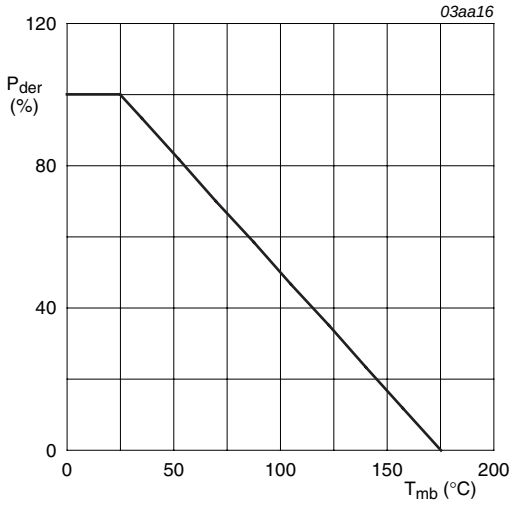
[2] Repetitive avalanche rating limited by average junction temperature of 170 °C.

[3] Refer to application note AN10273 for further information.



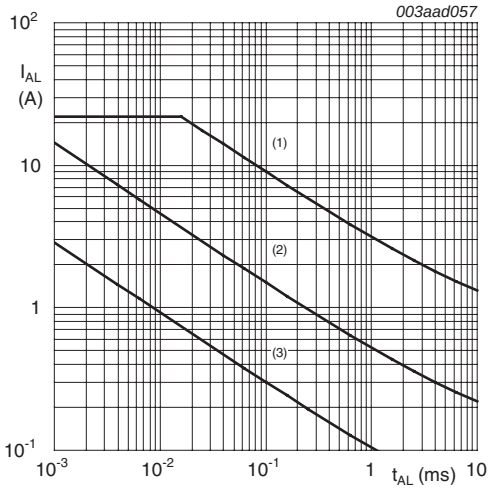
$V_{GS} \geq 10\,V$

Fig 1. Continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25°C)}} \times 100\,\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



(1) Single-pulse; $T_j = 25\,°C$.
(2) Single-pulse; $T_j = 150\,°C$.
(3) Repetitive.

Fig 3. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2.7	K/W

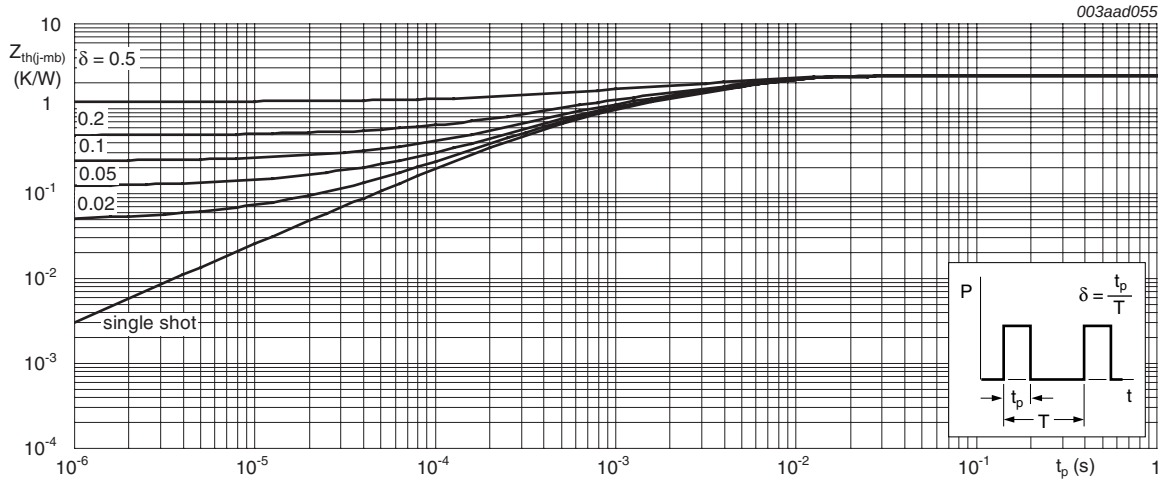


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

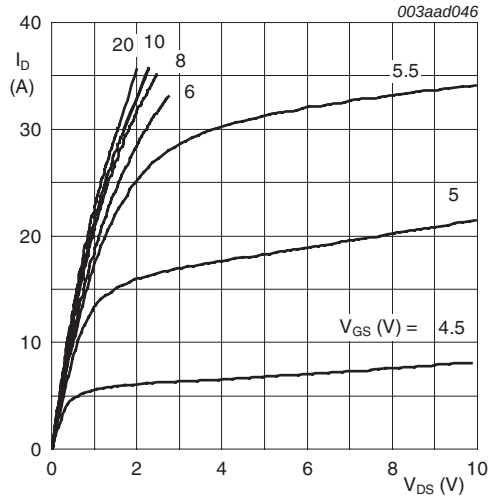
Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
$V_{(BR)DSS}$	drain-source breakdown voltage	I_D = 250 µA; V_{GS} = 0 V; T_j = -55 °C		73	-	-	V
		I_D = 250 µA; V_{GS} = 0 V; T_j = 25 °C		80	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS}; T_j = 175 °C; see Figure 11; see Figure 12		1	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = -55 °C; see Figure 11; see Figure 12		-	-	4.4	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = 25 °C; see Figure 11; see Figure 12		2	3	4	V
I_{DSS}	drain leakage current	V_{DS} = 80 V; V_{GS} = 0 V; T_j = 25 °C		-	-	1	µA
		V_{DS} = 80 V; V_{GS} = 0 V; T_j = 100 °C		-	-	100	µA
I_{GSS}	gate leakage current	V_{GS} = -20 V; V_{DS} = 0 V; T_j = 25 °C		-	-	100	nA
		V_{GS} = 20 V; V_{DS} = 0 V; T_j = 25 °C		-	-	100	nA
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 10 A; T_j = 100 °C; see Figure 13		-	-	81	mΩ
		V_{GS} = 10 V; I_D = 10 A; T_j = 25 °C	[2]	-	37	51	mΩ
R_G	internal gate resistance (AC)	f = 1 MHz		-	2	-	Ω
Dynamic characteristics							
$Q_{G(tot)}$	total gate charge	I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V		-	9	-	nC
		I_D = 25 A; V_{DS} = 40 V; V_{GS} = 10 V; see Figure 14; see Figure 15		-	11	-	nC
Q_{GS}	gate-source charge	I_D = 25 A; V_{DS} = 40 V; V_{GS} = 10 V; see Figure 14; see Figure 15		-	3.8	-	nC
$Q_{GS(th)}$	pre-threshold gate-source charge			-	1.9	-	nC
$Q_{GS(th-pl)}$	post-threshold gate-source charge			-	1.9	-	nC
Q_{GD}	gate-drain charge			-	2.3	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	V_{DS} = 40 V		-	5.2	-	V
C_{iss}	input capacitance	V_{DS} = 12 V; V_{GS} = 0 V; f = 1 MHz; T_j = 25 °C; see Figure 16		-	633	-	pF
C_{oss}	output capacitance			-	100	-	pF
C_{rss}	reverse transfer capacitance			-	50	-	pF
$t_{d(on)}$	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 Ω; V_{GS} = 10 V; $R_{G(ext)}$ = 4.7 Ω		-	9.2	-	ns
t_r	rise time			-	1	-	ns
$t_{d(off)}$	turn-off delay time			-	16	-	ns
t_f	fall time			-	2.4	-	ns

Table 6. Characteristics *…continued*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Source-drain diode						
V_{SD}	source-drain voltage	I_S = 15 A; V_{GS} = 0 V; T_j = 25 °C; see Figure 17	-	0.86	1.2	V
t_{rr}	reverse recovery time	I_S = 50 A; dI_S/dt = 100 A/µs; V_{GS} = 0 V; V_{DS} = 40 V	-	32	-	ns
Q_r	recovered charge		-	28	-	nC

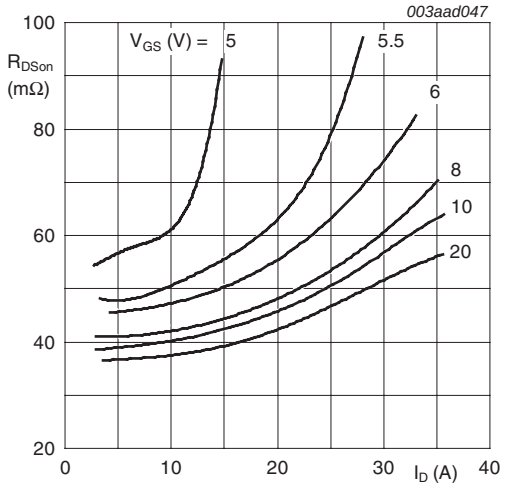
[1] Tested to JEDEC standards where applicable.

[2] Measured 3 mm from package.



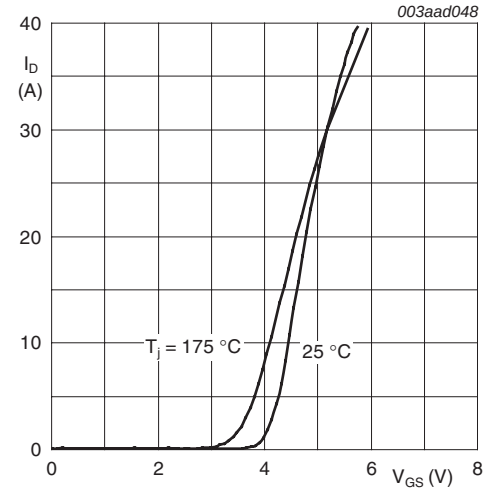
$T_j = 25\,°C; t_p = 300\mu s$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



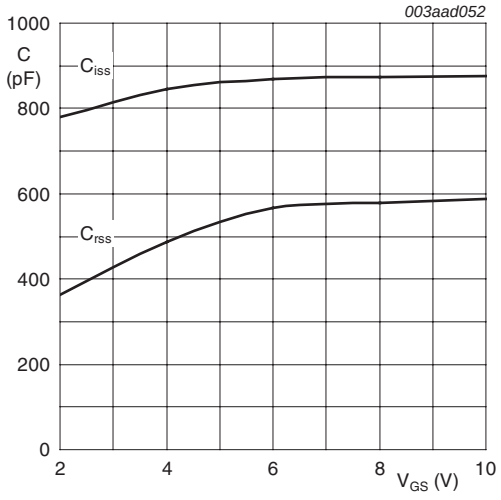
$T_j = 25\,°C; t_p = 300\mu s$

Fig 6. Drain-source on-state resistance as a function of drain current; typical values



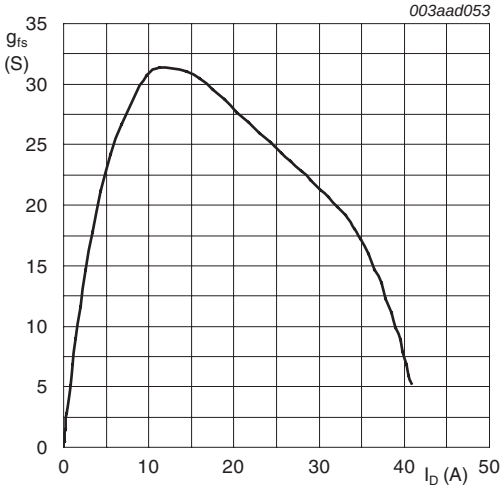
$V_{GS} = 0V$

Fig 7. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values



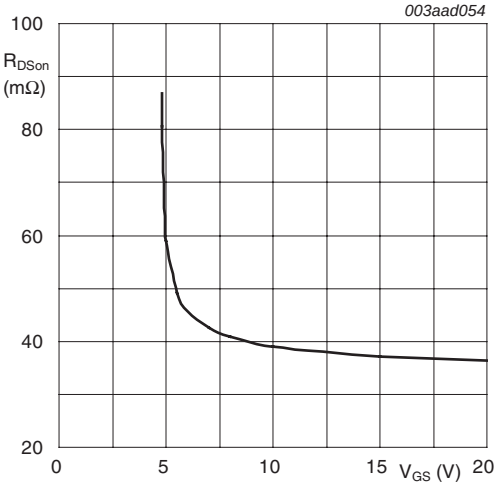
$V_{DS} = 0V; f = 1MHz$

Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



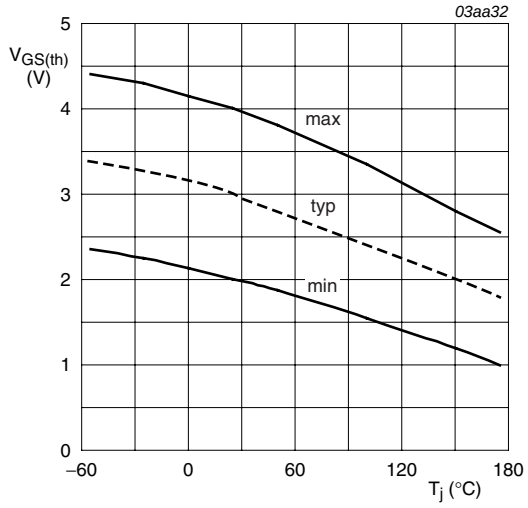
$T_j = 25\,°C; V_{DS} = 15V$

Fig 9. Forward transconductance as a function of drain current; typical values



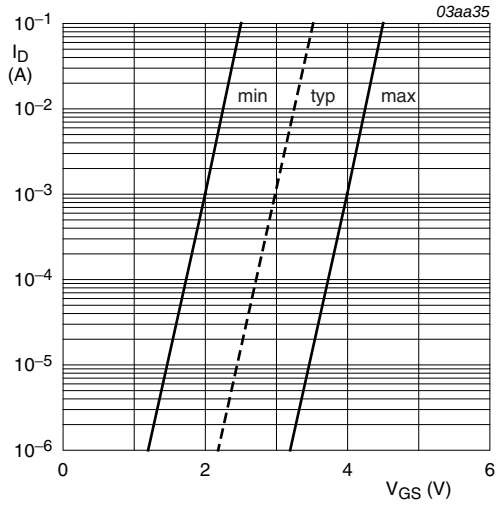
$T_j = 25\,°C; I_D = 10A$

Fig 10. Drain-source on-state resistance as a function of gate-source voltage; typical values



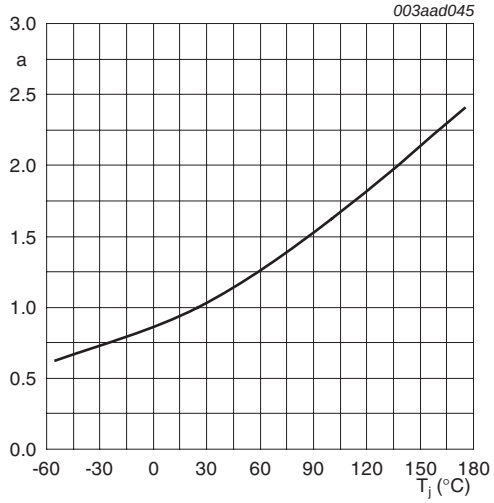
$I_D = 1mA; V_{DS} = V_{GS}$

Fig 11. Gate-source threshold voltage as a function of junction temperature



$T_j = 25\,°C; V_{DS} = 5V$

Fig 12. Sub-threshold drain current as a function of gate-source voltage



$$a = \frac{R_{DSon}}{R_{DSon(25°C)}}$$

Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

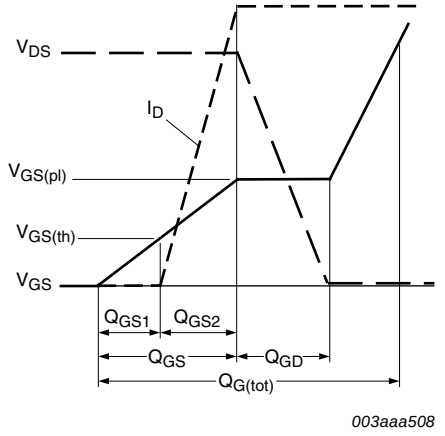
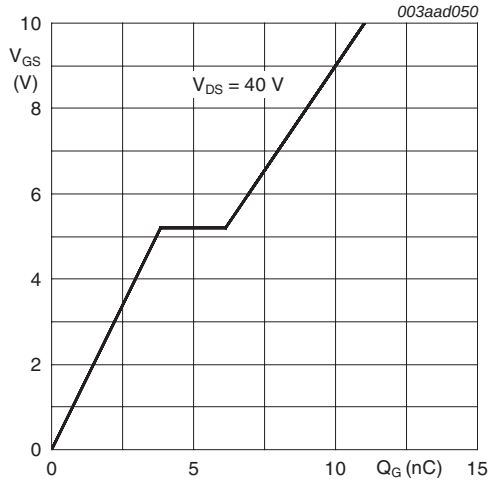
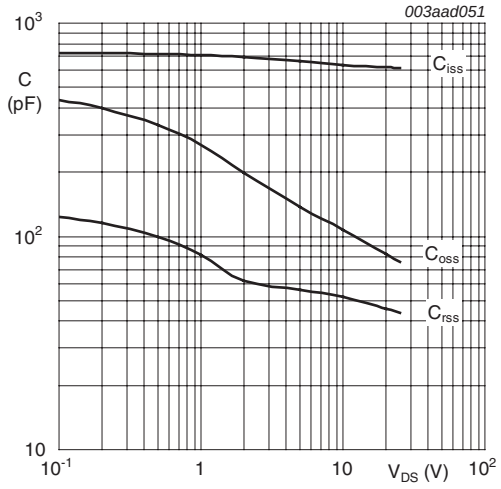


Fig 14. Gate charge waveform definitions



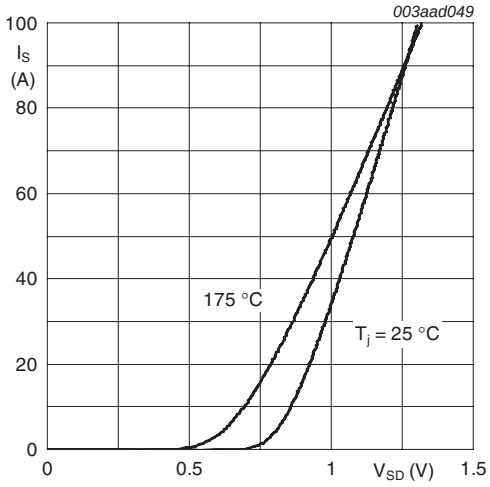
$T_j = 25\,°C; I_D = 25A$

Fig 15. Gate-source voltage as a function of gate charge; typical values



$V_{GS} = 0\,V; f = 1MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

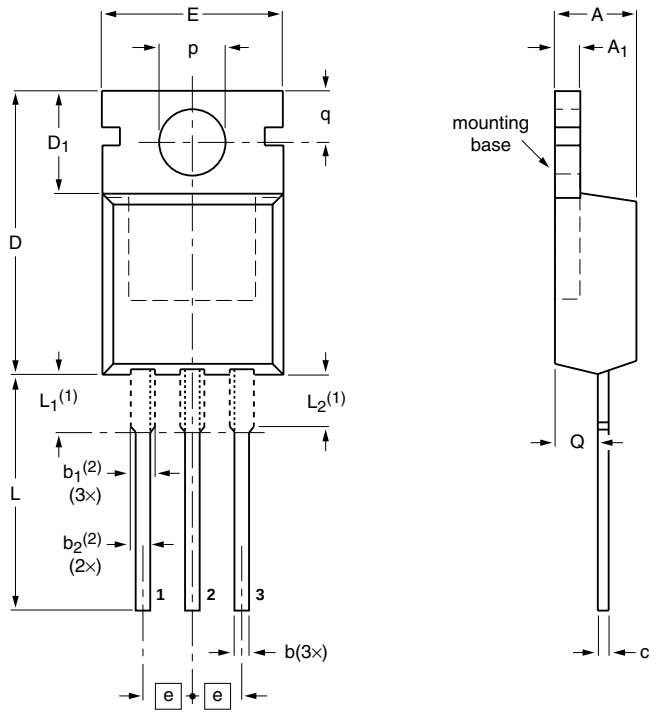


$V_{GS} = 0\,V$

Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB **SOT78**



DIMENSIONS (mm are the original dimensions)

UNIT	A	A_1	b	b_1(2)	b_2(2)	c	D	D_1	E	e	L	L_1(1)	L_2(1) max.	p	q	Q
mm	4.7 4.1	1.40 1.25	0.9 0.6	1.6 1.0	1.3 1.0	0.7 0.4	16.0 15.2	6.6 5.9	10.3 9.7	2.54	15.0 12.8	3.30 2.79	3.0	3.8 3.5	3.0 2.7	2.6 2.2

Notes

1. Lead shoulder designs may vary.
2. Dimension includes excess dambar.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT78		3-lead TO-220AB	SC-46			~~08-04-23~~ 08-06-13

Fig 18. Package outline SOT78 (TO-220AB)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN050-80PS_1	20090610	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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11. Contents

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